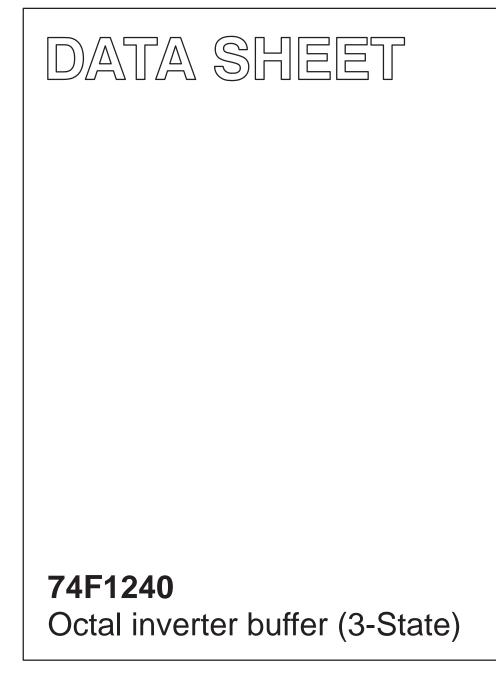
INTEGRATED CIRCUITS



Product specification Supercedes data of 1999 Jan 08 IC15 Data Handbook 2000 Jun 30



74F1240

FEATURES

- High impedance NPN base inputs for reduced loading (20µA in High and Low states)
- Low power, light loading
- Functional pin-for-pin equivalent of 74F240
- 1/30th the bus loading of 74F240
- Provides ideal interface and increase fan-out of MOS microprocessors
- Octal bus interface
- 3-State buffer outputs sink 64mA
- 15mA source current

DESCRIPTION

The 74F1240 is an octal buffer that is ideal for driving bus lines or buffer memory address registers. The outputs are capable of sinking 64mA and sourcing up to 15mA, producing very good capacitive drive characteristics. The device features two Output Enables, \overline{OEa} and \overline{OEb} , each controlling four of the 3-State outputs.

INPUT AND OUTPUT LOADING AND FAN OUT TABLE

| PINS | DESCRIPTION | 74F (U.L.) HIGH/LOW | LOAD VALUE HIGH/LOW |
|----------|-----------------------------------|------------------------|------------------------|
| lan, Ibn | Data inputs | 1.0/0.033 | 20μΑ/20μΑ |
| OEa, OEb | Output enable inputs (active Low) | 1.0/0.033 | 20μΑ/20μΑ |
| Yan, Ybn | Data outputs (74F1240) | 750/106.7 | 15mA/64mA |

NOTE: One (1.0) FAST unit load is defined as: 20μ A in the High state and 0.6mA in the Low state.

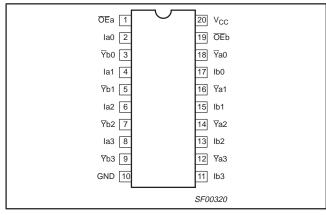
TYPETYPICAL
PROPAGATION
DELAYTYPICAL
SUPPLY CURRENT
(TOTAL)74F12403.5ns40mA

ORDERING INFORMATION

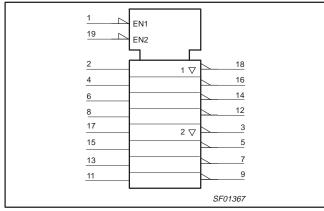
| DESCRIPTION | $\begin{array}{l} \text{COMMERCIAL RANGE} \\ \text{V}_{CC} = 5\text{V} \pm 10\%, \\ \text{T}_{amb} = 0^{\circ}\text{C to} + 70^{\circ}\text{C} \end{array}$ | DRAWING NUMBER |
|--------------------|---|-------------------|
| 20-pin plastic DIP | N74F1240N | SOT146-1 |
| 20-pin plastic SOL | N74F1240D | SOT163-1 |

74F1240

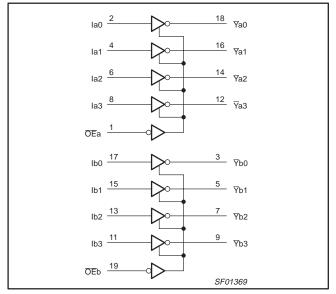
PIN CONFIGURATION



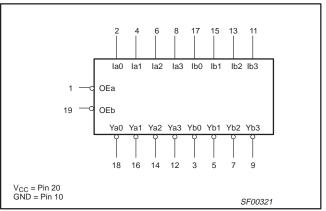
IEC/IEEE SYMBOL



LOGIC DIAGRAM



LOGIC SYMBOL



FUNCTION TABLE

| | INP | UTS | | OUTF | PUTS |
|-----|-----|-----|----|------|------|
| OEa | la | OEb | lb | Ya | Yb |
| L | L | L | L | Н | Н |
| L | Н | L | Н | L | L |
| Н | Х | Н | Х | Z | Z |

H = High voltage level L = Low voltage level

X = Don't care Z = High impedance "off" state

74F1240

ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limit set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

| SYMBOL | PARAMETER | RATING | UNIT |
|------------------|--|------------------|------|
| V _{CC} | Supply voltage | -0.5 to +7.0 | V |
| V _{IN} | Input voltage | -0.5 to +7.0 | V |
| I _{IN} | Input current | -30 to +5 | mA |
| V _{OUT} | Voltage applied to output in High output state | –0.5 to V_{CC} | V |
| I _{OUT} | Current applied to output in Low output state | 128 | mA |
| T _{amb} | Operating free-air temperature range | 0 to +70 | °C |
| T _{stg} | Storage temperature range | -65 to +150 | °C |

RECOMMENDED OPERATING CONDITIONS

| SYMBOL | DADAMETED | | LINUT | | |
|------------------|--------------------------------------|-----|-------|-----|------|
| STMBOL | PARAMETER | MIN | NOM | MAX | UNIT |
| V _{CC} | Supply voltage | 4.5 | 5.0 | 5.5 | V |
| V _{IH} | High-level input voltage | 2.0 | | | V |
| V _{IL} | Low-level input voltage | | | 0.8 | V |
| I _{IK} | Input clamp current | | | -18 | mA |
| I _{OH} | High-level output current | | | -15 | mA |
| I _{OL} | Low-level output current | | | 64 | mA |
| T _{amb} | Operating free-air temperature range | 0 | | +70 | °C |

74F1240

DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

| CVMDO: | DADAMETER | | | | | | | | | |
|------------------|---|------------------------------|--|-------------------------|----------------------|-------|----------------------|------|----|--|
| SYMBOL | PARAMETER | | TEST CONDITIONS ¹ | | | | TYP ² MAX | | | |
| | | | | 1 | ±10% V _{CC} | 2.4 | | | V | |
| V | | | V _{CC} = MIN V _{II} = MAX | I _{OH} = -3mA | ±5% V _{CC} | 2.7 | 3.3 | | V | |
| V _{OH} | High-level output voltage | | $V_{IH} = MIN$ | I _{OH} = -15mA | ±10% V _{CC} | 2.0 | | | V | |
| | | | | $I_{OH} = -15111A$ | $\pm 5\% V_{CC}$ | 2.0 | | | V | |
| M | | | $V_{CC} = MIN$ $V_{II} = MAX$ | I _{OL} = 48mA | ±10% V _{CC} | | 0.38 | 0.55 | V | |
| V _{OL} | Low-level output voltage | | $V_{IL} = MIAX$ $V_{IH} = MIN$ | I _{OL} = 64mA | ±5% V _{CC} | | 0.42 | 0.55 | V | |
| V _{IK} | Input clamp voltage | $V_{CC} = MIN, I_I = I_{IK}$ | | | | -0.73 | -1.2 | V | | |
| lı | Input current at maximum input voltage | | $V_{CC} = 0.0V, V_{I} = 7.0V$ | | | | | 100 | μA | |
| I _{IH} | High-level input current | | $V_{CC} = MAX,$ | $V_{I} = 2.7 V$ | | | | 20 | μA | |
| IIL | Low-level input current | | V _{CC} = MAX, | $V_{ } = 0.5V$ | | | | -20 | μA | |
| I _{OZH} | Off-state output current, High-level voltage applied | | V _{CC} = MAX, | $V_{0} = 2.7 V$ | | | | 50 | μA | |
| I _{OZL} | Off-state output current, Low-level voltage applied | | V _{CC} = MAX, | $V_{O} = 0.5V$ | | | | -50 | μΑ | |
| I _{OS} | Short-circuit output current ³ | | $V_{CC} = MAX$ | | | -100 | | -225 | mA | |
| | | I _{CCH} | | | | | 22 | 30 | mA | |
| I _{CC} | Supply current (total) | I _{CCL} | V _{CC} = MAX | | | | 58 | 75 | mA | |
| | | I _{CCZ} | | | | | 44 | 58 | mA | |

NOTES:

1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type. 2. All typical values are at $V_{CC} = 5V$, $T_{amb} = 25^{\circ}C$. 3. Not more than one output should be shorted at a time. For testing I_{OS} , the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

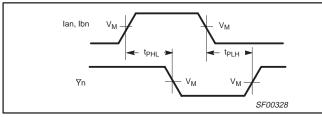
AC ELECTRICAL CHARACTERISTICS

| | | | | | LIM | ITS | | |
|------------------|----------------------|-------------------|-----|--|-----|----------------------|--|------|
| SYMBOL | PARAMETER | TEST CONDITION | V | _{amb} = +25 / _{CC} = +5.0 50pF, R _L = | V | V _{CC} = +5 | C to +70°C .0V ± 10% R _L = 500Ω | UNIT |
| | | | MIN | TYP | MAX | MIN | MAX | |
| t _{PLH} | Propagation delay | Waveform 1 | 3.0 | 4.5 | 6.5 | 2.5 | 7.5 | ns |
| t _{PHL} | Ian, Ibn, to Yn | | 1.5 | 2.5 | 4.5 | 1.5 | 5.0 | ns |
| t _{PZH} | Output Enable time | Waveform 3 | 3.0 | 5.5 | 7.5 | 3.0 | 8.0 | ns |
| t _{PZL} | to High or Low level | Waveform 4 | 4.0 | 7.0 | 9.0 | 4.0 | 9.5 | ns |
| t _{PHZ} | Output Disable time | Waveform 3 | 2.0 | 4.0 | 6.0 | 2.0 | 6.5 | ns |
| t _{PLZ} | to High or Low level | Waveform 4 | 2.0 | 4.0 | 5.5 | 2.0 | 6.0 | ns |

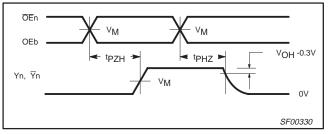
74F1240

AC WAVEFORMS

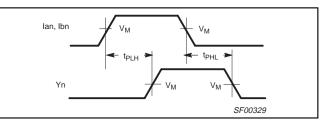
For all waveforms, $V_M = 1.5V$.



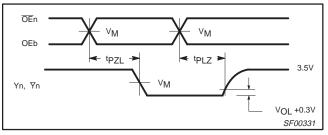
Waveform 1. For Inverting Outputs

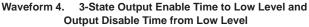


Waveform 3. 3-State Output Enable Time to High Level and Output Disable Time from High Level

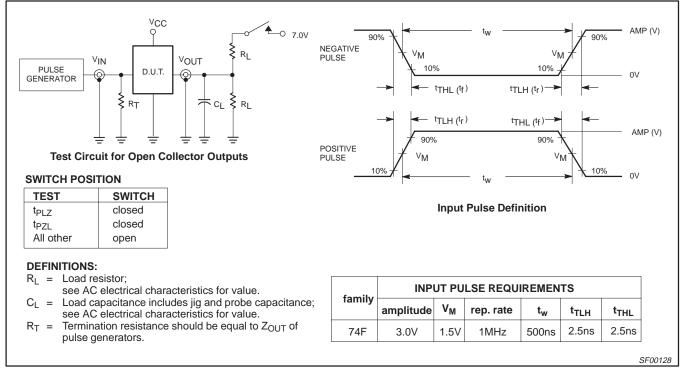


Waveform 2. For Non-inverting Outputs



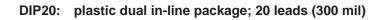


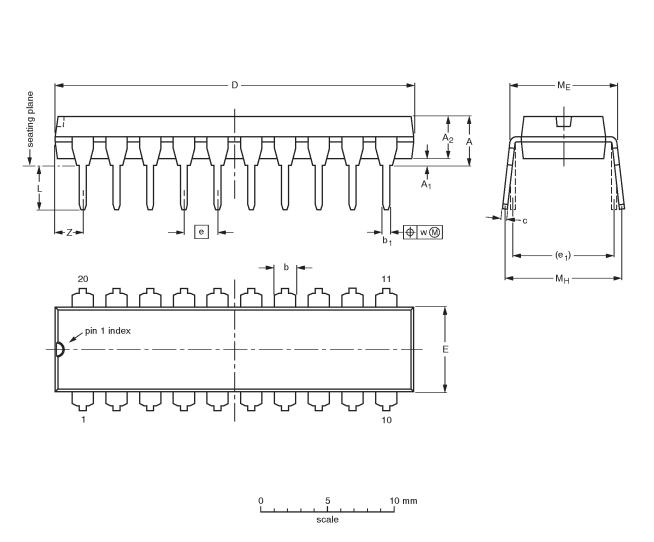
TEST CIRCUIT AND WAVEFORMS



74F1240

Product specification





DIMENSIONS (inch dimensions are derived from the original mm dimensions)

| UNIT | A max. | A ₁ min. | A ₂ max. | b | b ₁ | с | D ⁽¹⁾ | Е ⁽¹⁾ | e | e ₁ | L | M _E | M _H | w | Z ⁽¹⁾ max. |
|--------|-----------|------------------------|------------------------|----------------|----------------|----------------|------------------|------------------|------|----------------|--------------|----------------|----------------|-------|--------------------------|
| mm | 4.2 | 0.51 | 3.2 | 1.73 1.30 | 0.53 0.38 | 0.36 0.23 | 26.92 26.54 | 6.40 6.22 | 2.54 | 7.62 | 3.60 3.05 | 8.25 7.80 | 10.0 8.3 | 0.254 | 2.0 |
| inches | 0.17 | 0.020 | 0.13 | 0.068 0.051 | 0.021 0.015 | 0.014 0.009 | 1.060 1.045 | 0.25 0.24 | 0.10 | 0.30 | 0.14 0.12 | 0.32 0.31 | 0.39 0.33 | 0.01 | 0.078 |

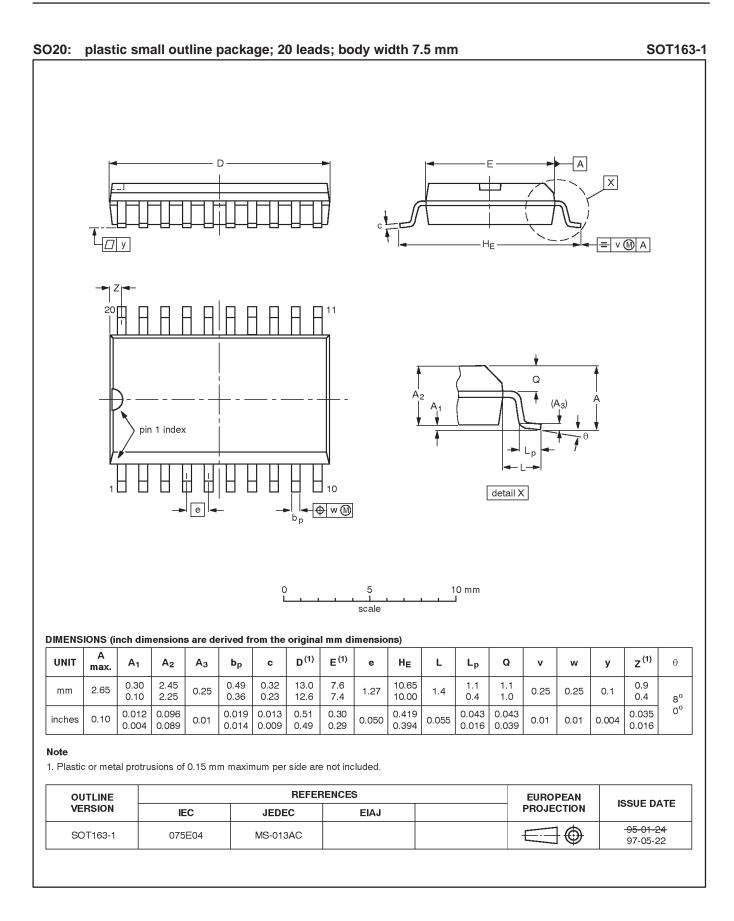
Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

| OUTLINE | | REFEF | RENCES | EUROPEAN | ISSUE DATE | |
|----------|-----|-------|--------|----------|------------|-----------------------------------|
| VERSION | IEC | JEDEC | EIAJ | | PROJECTION | ISSUE DATE |
| SOT146-1 | | | SC603 | | | -92-11-17- 95-05-24 |

SOT146-1

74F1240



74F1240

NOTES

74F1240

Data sheet status

| Data sheet status | Product status | Definition ^[1] |
|---------------------------|-------------------|--|
| Objective specification | Development | This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice. |
| Preliminary specification | Qualification | This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product. |
| Product specification | Production | This data sheet contains final specifications. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product. |

[1] Please consult the most recently issued datasheet before initiating or completing a design.

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Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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